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CONFIRMATION NO. 8865

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<b>APPLICANTS</b>  Yehiel Gotkis, Fremont, CA;  Rodney Kistler, Los Gatos, CA; Aleksander Owczarz, San Jose, CA; David Hemker, San Jose, CA; Nicolas J. Bright, San Jose, CA;					
** CONTINUING DATA ***** NO <sub>DD</sub>					
** FOREIGN APPLICATIONS ***** NO <sub>DD</sub>					
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 12/17/2003					
Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 (a-d) conditions <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after met Verified and <i>Deanna Dams</i> on Acknowledged Examiner's Signature Initials		STATE OR  COUNTRY CA	SHEETS  DRAWING 11	TOTAL  CLAIMS 24	INDEPENDENT  CLAIMS 5
<b>ADDRESS</b> 25920 MARTINE PENILLA & GENCARELLA, LLP 710 LAKEWAY DRIVE SUITE 200 SUNNYVALE, CA 94085					
<b>TITLE</b> Method and apparatus for wafer mechanical stress monitoring and wafer thermal stress monitoring					
FILING FEE	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees ( Filing ) <input type="checkbox"/> 1.17 Fees ( Processing Ext. of time )		